

Notice of References Cited	Application/Control No. 10/692,516		Applicant(s)/Patent Under Reexamination YEOW ET AL.	
	Examiner VANEL FRENEL		Art Unit 3687	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0004784	01-2003	Li et al.	705/10
*	B	US-2004/0034581	02-2004	Hill et al.	705/28
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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